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Supporting information for article:

A simple correction for the parallax effect in X-ray pair distribution function measurements

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Supplementary Information for: A simple correction for the parallax effect in X-ray pair distribution function measurements

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The refined coefficients and their error values are listed in the following table. They were implemented using the `th2_offset` function in Topas. The coefficients are however calculated using the 2θ values in radians. Hence, a plot has been included below to show the shift of 2θ in degrees. A comparison between refining all standards at the same time and each one individually has also been included. It should be noted that these coefficients will vary for each individual experimental setup.

Table 1: Offset polynomial coefficients for the parallax correction

Refinement	a coefficient	b coefficient
All standards	0.28(3)	0.005(12)
CeO ₂	0.23(4)	0.037(12)
Ni	0.36(4)	0.004(28)
LaB ₆	0.24(5)	0.040(26)

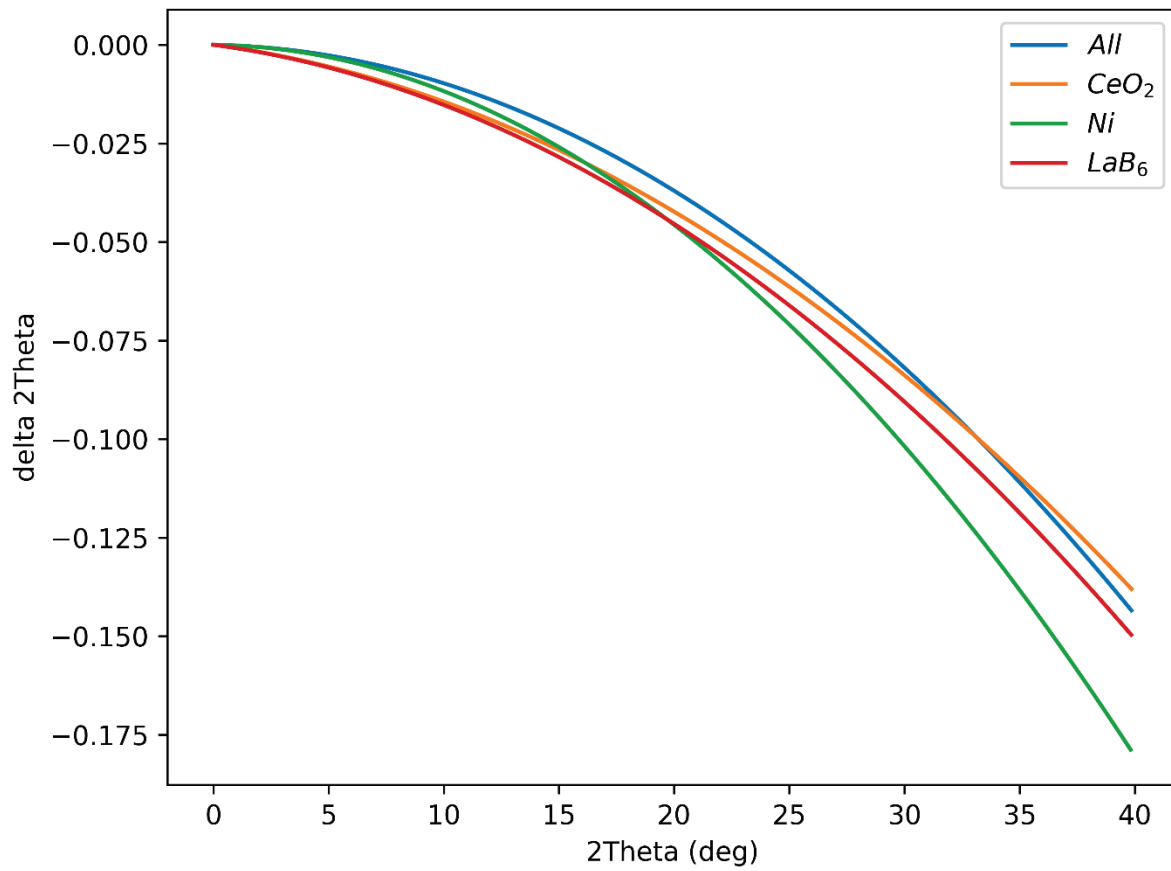


Figure 1: Offset polynomials along the 2θ range in degrees.